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**AEHR TEST SYSTEMS RECEIVES FIRST ORDER FOR NEW
ADVANCED BURN-IN AND TEST SYSTEM (ABTS) FROM
INTEGRATED SERVICE TECHNOLOGY IN TAIWAN**

Fremont, CA (July 14, 2008) - Aehr Test Systems (Nasdaq: AEHR), a leading supplier of semiconductor test and burn-in equipment, today announced it has received the first order for the Company's new Advanced Burn-in and Test System (ABTS) from Integrated Service Technology (iST) in Taiwan. The system is configured for burning-in and testing advanced logic devices. This follows a thorough evaluation of a demonstration system delivered to iST in May of this year.

"This ABTS system is the first in a series of new products that will be introduced over the next several quarters for testing packaged devices. This new technology is based on our successful FOXTM-1 full-wafer contact burn-in and test system," said Greg Perkins, vice president of worldwide sales and service at Aehr Test Systems. "Although numerous FOXTM systems are currently in high volume production in many parts of the world, this is the first version of the ABTS package part TDBI systems based on the same electronics. Other members of the ABTS family will focus on high-power logic and memory devices."

"We are committed to providing the most competitive solutions to our customers, and ABTS is a powerful extension of that commitment," said Christine Lee, Manager of Corporate Communication & Industrial Competitiveness Planning Division of Integrated Service Technology. "By working with Aehr, we are able to achieve the highest level of customer satisfaction."

"We understand the needs customers have for burning-in and testing advanced logic devices," commented Rick Wu, VP of Integrated Engineering Service Division of Integrated Service Technology. "Therefore, we dedicate our knowledge and service expertise to help customers successfully compete in their market space."

The ABTS family of products is based on a completely new hardware and software architecture that addresses not only today's devices, but also future devices for many years to come. The system can test and burn-in memory devices as well as both high- and low-power logic devices. The ABTS system can be configured to provide individual device temperature control for devices up to 75W or more and with up to 320 I/O channels. It uses N+1 redundancy technology for many key components in the system to provide the highest possible system uptime.

About Integrated Service Technology

Integrated Service Technology is one of the largest Reliability Engineering, IC Failure Analysis and Integration Project Service companies in the Asia-Pacific region, and it also has a significant presence in other world-wide markets. The company's broad integration project service portfolio includes developing leading testing, verification, evaluation, debugging, and analysis project service technologies: mastering advanced semiconductor nano-processes, protecting intellectual property and green environmental trends that combine electrical parameter analysis, reliability engineering and other technologies to provide the most timely high quality comprehensive service, accelerating customer product development and time to market plan. Headquartered in Taiwan, Integrated Service Technology has service and support offices around the world, including the U.S, Japan, and China. For more information, please visit: www.istgroup.com.

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a leading worldwide provider of systems for burning-in and testing memory and logic integrated circuits and has an installed base of more than 2,500 systems worldwide. Aehr Test has developed and introduced several innovative products, including the ABTS, FOX, MTX and MAX systems and the DiePak[®] carrier. The FOX system is a full wafer contact test and burn-in system. The MTX system is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously. The MAX system can effectively burn-in and functionally test complex devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company's website at www.aehr.com.

Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding customer demand and acceptance of Aehr Test's products. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by customers of the ABTS technology, acceptance by customers of the ABTS systems shipped upon receipt of a purchase order and the ability of new products to meet customer needs or perform as described. See Aehr Test's recent 10-K, 10-Q and other reports from time to time filed with the Securities and Exchange Commission (SEC) for a more detailed description of the risks facing our business. Aehr Test Systems disclaims any obligation to update information

contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

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